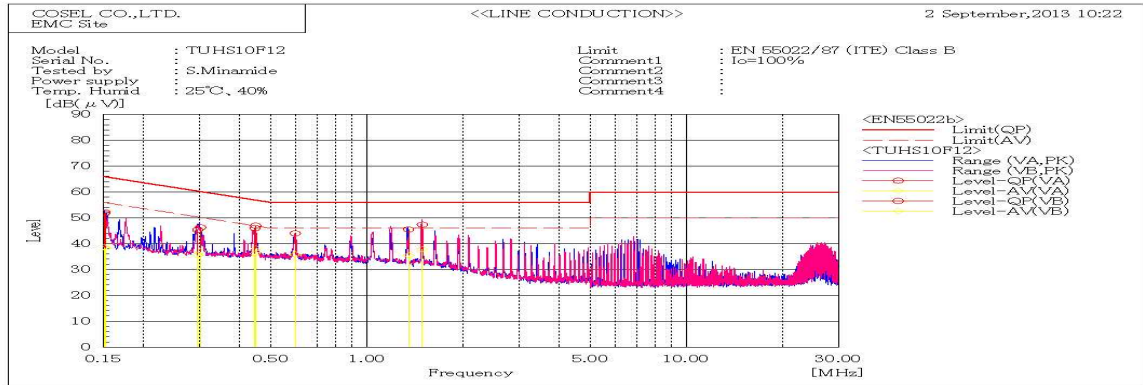
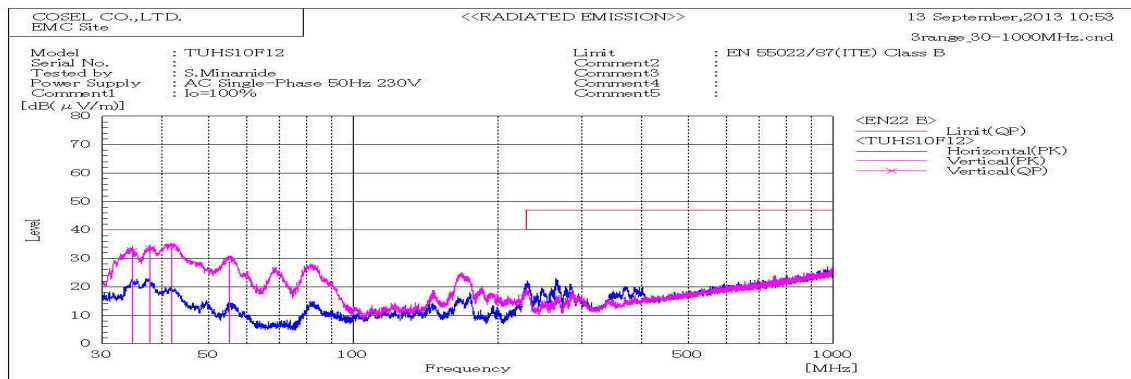


DATA SHEET		Date	16-Dec-13
Model	TUHS10F12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



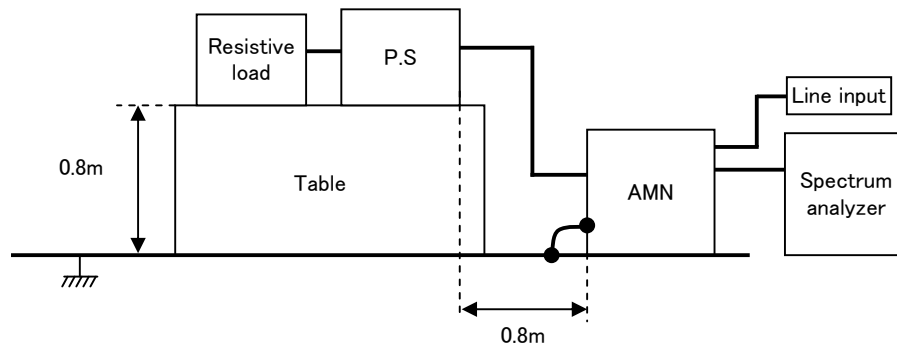
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15217		VA	31.8	18	20.3	52.1	383.3	65.9	55.9	13.8	13.8	Pass	
0.15121		VB	31.5	18.04	20.2	51.7	38.6	65.9	55.9	14.2	14.2	Pass	
0.29598		VB	25.2	15.5	20.1	45.3	35.6	60.4	50.4	15.1	15.1	Pass	
0.30227		VA	26.2	16.9	20.1	46.3	37	60.2	50.2	13.9	13.9	Pass	
0.44992		VA	26.9	18	20.1	47	38	56.9	46.9	9.9	9.9	Pass	
0.44725		VB	25.9	16.1	20.1	46	36.2	56.9	46.9	10.9	10.9	Pass	
0.59767		VA	23.9	15.7	20.1	44	35.8	56	46	12	12	Pass	
1.35069		VA	25.3	15.2	20.2	45.5	35.4	56	46	10.5	10.5	Pass	
1.49248		VB	27.2	17.7	20.2	47.4	37.9	56	46	8.6	8.6	Pass	



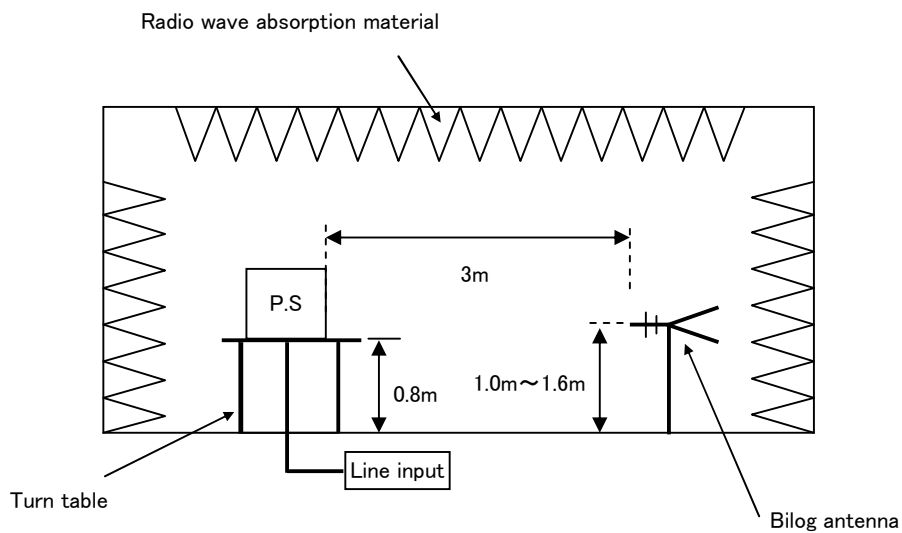
Frequency MHz	Polariz ation	Stabilit y	Reading dB(uV)		Factor dB(1/m)	Level dB(uV/m)		Limit dB(uV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP			QP							
34.677	V	Stable	47.5	-14.7		32.8		40	7.2	Pass	100	348	
37.677	V	Stable	48.7	-15.2		33.5		40	6.5	Pass	104	299	
41.742	V	Stable	49.7	-16		33.7		40	6.3	Pass	104	276	
55.127	V	Stable	52.8	-23.9		28.9		40	11.1	Pass	104	11	

DATA SHEET		Date	16-Dec-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	S.Minamide

1. Line conduction



2. Radiated emission



Conditions

Test: EMI

Model Name: TUHS10F□□

○ Photographs of Test Set-Up

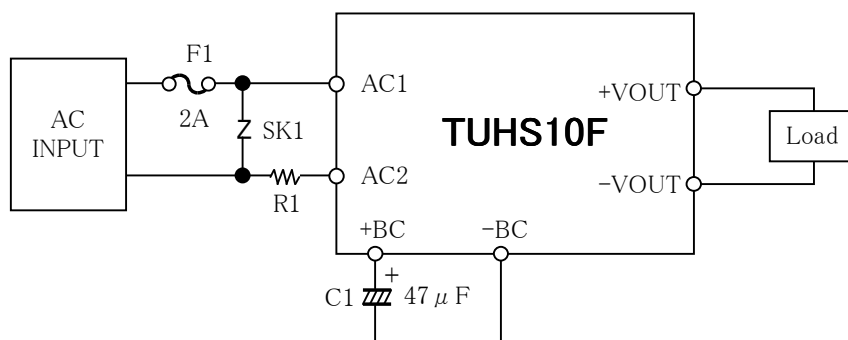
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 2K100JA (TAMURA THERMAL DEVICE)

SK1: S10K385E2K1 (TDK EPCOS)

2A
10Ω

Fig.1 Testing circuitry